

Time (CET)	Title	Presenters, Research Project Members
09:00 – 10:20	Opening Session Welcome, Greetings, Agenda Overview Opening speeches Peter Wewerka (CEO Advantest Europe), Wolfram Ressel (Rector University of Stuttgart) Overview on the GS-IMTR (Jochen Rivoir, Dirk Pflüger) Best Paper Award Outlook to the 2 nd round	Matthias Sauer, Dirk Pflüger, Hussam Amrouch
10:20 – 10:40	Break	
10:40 – 11:20	Keynote “Why traditional tests will fail in emerging technologies”	Said Hamdioui (TU Delft)
11:20 – 11:40	Graduate School ASIC	Jens Anders, Hussam Amrouch
11:45 – 12:40	Lunch Break	
12:40 – 13:00	Advanced (Machine) Learning Techniques P2: Visual Analytics for Post-Silicon Validation P6: Deep learning based variable selection for post-silicon validation	Andrés Lalama, Thomas Ertl, Daniel Weiskopf, Steffen Koch
13:00 – 13:20	P3: Self-Learning Tuning for Post-Silicon Validation	Yiwen Liao, Bin Yang
13:20 – 13:40	P3: Self-Learning Tuning for Post-Silicon Validation	Peter Domanski, Dirk Pflüger
13:40 – 14:00	P10: Hyperdimensional Computing for Chip Testing - Towards Learning Fast from Little Data	Paul Genßler, Hussam Amrouch
14:00 – 14:20	Break	
14:20 – 14:40	Associated Projects / Session title still missing PA1: Variation-Aware Test Method to Increase the Reliability of Nano-Scale Devices	Paria Haghi, Hans-Joachim Wunderlich
14:40 – 15:00	PA3: Dependable Integration of Reconfigurable Scan Networks for Test and Diagnosis	Natalia Lylina, Hans-Joachim Wunderlich
15:00 – 15:20	PA4: Online Evaluation of system health state	Hanieh Jafarzadeh, Hans-Joachim Wunderlich
15:20 – 15:40	Advanced Hardware Design P7: Miniaturized Millimeter-Wave RF Interface Module	Athanasios Gatzastras, Sebastien Chartier, Ingmar Kallfass
15:40 – 16:00	P9: Design for Testing and Reliability in the Presence of Transistor Self-Heating for Advanced Technologies	Florian Klemme, Hussam Amrouch
16:00 – 16:20	Break	
16:20 – 16:40	Reliability and Privacy of Semiconductor Testing P4: Secure and Privacy-Preserving Semiconductor Testing	Sebastian Hasler, Ralf Küsters
16:40 – 17:00	P8: Software Test Suite Optimization for Complex High Data-Volume SW	Maik Betka, Steffen Becker, Andre van Hoorn, Stefan Wagner
17:00 – 17:20	System Level Test P1: Systematic Analysis of System-Level Test Fails	Nourhan Elhamawy, Jens Anders, Ilia Polian
17:20 – 17:40	P5: Automated Generation of System-Level Test Programs for Characterization of Parametric Device Properties	Denis Schwachhofer, Ilia Polian, Stefan Wagner, Steffen Becker
17:40 – 18:00	Closing	Matthias Sauer, Dirk Pflüger, Hussam Amrouch